

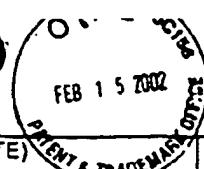
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QUERY CONTROL FORM		RTIS USE ONLY	
Application No.	09/996,299	Prepared by	NBB
Examiner-GAU	Pham-2814	Date	10/11/04
		No. of queries	1
		Tracking Number	06006908
		Week Date	9/6/04
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JACKET

a. Serial No.	f. Foreign Priority	k. Print Claim(s)	p. PTO-1449
b. Applicant(s)	g. Disclaimer	l. Print Fig.	q. PTOL-85b
c. Continuing Data	h. Microfiche Appendix	m. Searched Column	r. Abstract
d. PCT	i. Title	n. PTO-270/328	s. Sheets/Figs
e. Domestic Priority	j. Claims Allowed	o. PTO-892	t. Other

SPECIFICATION	MESSAGE
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CLAIMS	<i>Thank you</i>
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Sheet 2 of 2

FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

INFORMATION DISCLOSURE
STATEMENT BY APPLICANT
(37 CFR 1.98(b))

Attorney Docket No.:
L&L-I0178

Applic. No.
09/996,279

Applicant

Lothar Risch et al.

Filing Date
November 28, 2001

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U.S. PATENT DOCUMENTS

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FOREIGN PATENT DOCUMENT

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	J						
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	Pikus, F.G. et al.: "Nanoscale field-effect transistors: An ultimate size analysis", Appl. Phys. Lett. 1971, Vol. 25, December 22, 1997, pp. 3661-3663
	P	

EXAMINER _____ DATE CONSIDERED _____

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